

<b>Notice of References Cited</b>	Application/Control No. 10/047,717	Applicant(s)/Patent Under Reexamination KNAPP, RICHARD J.	
	Examiner Tan Dean D. Nguyen	Art Unit 3689	Page 1 of 1

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*	C	US-6,282,550	08-2001	Venkatesan et al.	707/104.1
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**NON-PATENT DOCUMENTS**

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